

<b>Notice of References Cited</b>	Application/Control No. 10/536,655	Applicant(s)/Patent Under Reexamination BAYER ET AL.	
	Examiner David D. Le	Art Unit 3681	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,155,376 A	12-2000	Cheng, Wangquan	180/444
*	B	US-2006/0011405 A1	01-2006	Bayer et al.	180/421
*	C	US-6,925,371 B2	08-2005	Yasui et al.	701/72
*	D	US-4,726,257	02-1988	Nelson, Donald F.	475/330
*	E	US-5,415,595 A	05-1995	Nelson, Bertel S.	475/7
*	F	US-5,029,659	07-1991	Saito, Naoki	180/443
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 209998 A1	02-2002	World Intellect	BUNDSCHU et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.